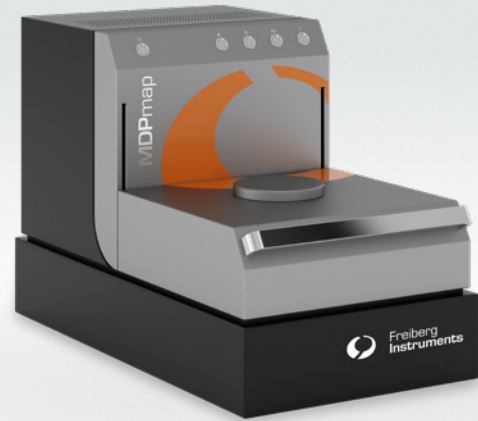


Microwave Detected Photoconductivity

Minority carrier lifetime and resistivity

Contactless and destruction free lifetime imaging (μ PCD/MDP (QSS), photoconductivity and resistivity check according to semi standard SEMI PV9-1110.



Learn more

Excitation

355–1550 nm

pulsed or CW

Sample size up to

**300 mm
wafers**

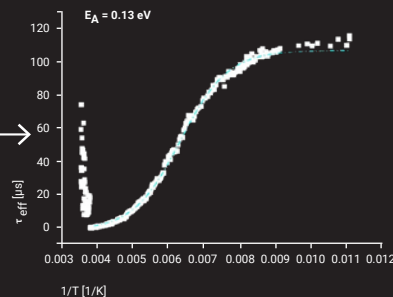
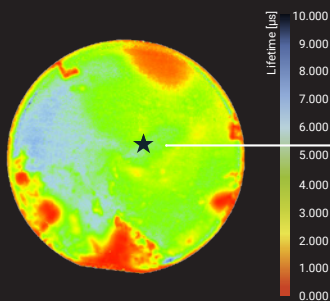
Materials

**Si, SiC, GaN, GaAs,
InP, Ga₂O₃ and more**

Measurement of
epitaxial layers down to

2 μm

Recombination sites



Up to

8

orders of magnitude
of injection dependent
measurements can
be achieved

Minority carrier lifetime

**20 ns –
100 ms**

Resistivity range (low)

**10–100
mOhm cm**

Resistivity range (high)

**0.3–5
Ohm cm**

Temperature range

**RT to 520 K
(30–80 K)**

on request